


<b>Search Notes</b>  	<b>Application/Control No.</b>  10562820	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAKUWA ET AL.
	<b>Examiner</b>  DANIEL TEKLE	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST SEARCH DATA BASE (USPAT; USPGPUB; USOCR; JPO; EPO; DERWENT)	05/08/2010	D.T.
SEARCH QUERY ATTACHED	05/08/2010	D.T.
INVENTOR SEARCH	05/08/2010	D.T.
NPL	05/08/2010	D.T.
QEM	05/05/2010	D.T.
SEARCH UPDATED	10/22/2010	D.T.
386/\$ (TEXT SEARCH)	10/22/2010	D.T.
INVENTOR SEARCH	10/22/2010	D.T.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/D. T./ Examiner.Art Unit 2621	
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